

Notice of References CitedApplication/Control No.
09/739,385Applicant(s)/Patent Under
Reexamination
BOTTORFF ET ALExaminer
Gregory B SefcheckArt Unit
2C62

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0181499 A1	12-2002	Kfir et al.	370/466
	B	US-2002/0037018	03-2002	Lentine et al.	370/521
	C	US-6,704,326 B2	03-2004	Russell et al.	370/466
	D	US-6,658,021	12-2003	Bromley et al.	370/466
	E	US-6,636,529 B1	10-2003	Goodman et al.	370/489
	F	US-6,608,834 B1	08-2003	Lewin et al.	370/395.53
	G	US-6,567,413 B1	05-2003	Denton et al.	370/465
	H	US-6,496,519 B1	12-2002	Russell et al.	370/465
	I	US-6,414,968 B1	07-2002	Kulkarni et al.	370/465
	J	US-8,389,036 B1	05-2002	Stewart et al.	370/466
	K	US-6,014,708 A	01-2000	Klish, Cyprian T.	709/232
	L	US-5,179,555 A	01-1993	Videlock et al.	370/402
	M	US-5,040,170	08-1991	Upp et al.	398/50

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO0074286 A1	12-2000	PCT	Muller	H04J 3/16
	O	EP001006751A2	06-2000	EU	Ramsden et al.	H04Q 11/04
	P	WO0074282 A2	05-2000	PCT	Martin et al.	H04J 3/00
	Q	EP000693833A1	01-1996	EU	Krisher	H04J 3/16
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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